

Notice of References Cited		Application/Control No. 10/615,403	Applicant(s)/Patent Under Reexamination ONO ET AL.	
		Examiner Kevin M. Bernatz	Art Unit 1794	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B US-5,481,527	01-1996	Kasanuki et al.	369/126
*	C US-7,020,064	03-2006	Kim et al.	369/126
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*	E US-5,226,029	07-1993	Takanashi et al.	369/100
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M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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